

EAST - [Untitled1:1]

File View Edit Tools Window Help

Drafts

- Pending**
- Active**
 - L1: (16) "5898186"
 - L2: (9) "5994915"
 - L3: (762) (stress\$3 near2 test\$3) and leakage
 - L4: (138) (stress\$3 near2 test\$3) same leakage
 - L5: (42) (stress\$3 near2 test\$3) with leakage
 - L6: (97144) 4 and common global
 - L8: (2) 7 and (single adj chip)
 - L7: (77) 4 and (common global)
- Failed
- Saved
- Favorites
- Tagged (0)

DBs: USPAT; US-PGPUB; EPO; JPO

Default operator: OR

☐ Plures

☐ Highlight all hit terms in body

	Type	L #	Hits	Search Text	DBs
1	BRS	L1	16	"5898186"	USPAT; US-PGPUB; EPO; JPO
2	BRS	L2	9	"5994915"	USPAT; US-PGPUB; EPO; JPO
3	BRS	L3	762	(stress\$3 near2 test\$3) and leakage	USPAT; US-PGPUB; EPO; JPO
4	BRS	L4	138	(stress\$3 near2 test\$3) same leakage	USPAT; US-PGPUB; EPO; JPO
5	BRS	L5	42	(stress\$3 near2 test\$3) with leakage	USPAT; US-PGPUB; EPO; JPO
6	BRS	L6	97144	4 and common global	USPAT; US-PGPUB; EPO; JPO
7	BRS	L8	2	7 and (single adj chip)	USPAT; US-PGPUB; EPO; JPO
8	BRS	L7	77	4 and (common global)	USPAT; US-PGPUB; EPO; JPO

Ready

EAST - [Untitled1:1]

FileViewEditToolsWindowHelp

Drafts

Pending

Active

L1: (0) memory same (global adj (wordline word-l

L2: (2) memory and (global adj (wordline word-lir

Failed

Saved

Favorites

Tagged (0)

UDC

Queue

Trash

DBs

USPAT; US-PGPUB; EPO; JPO

Default operator

OR

Plural

Highlight all hit terms locally

1183 items

USPAT; US-PGPUB; EPO; JPO

Image

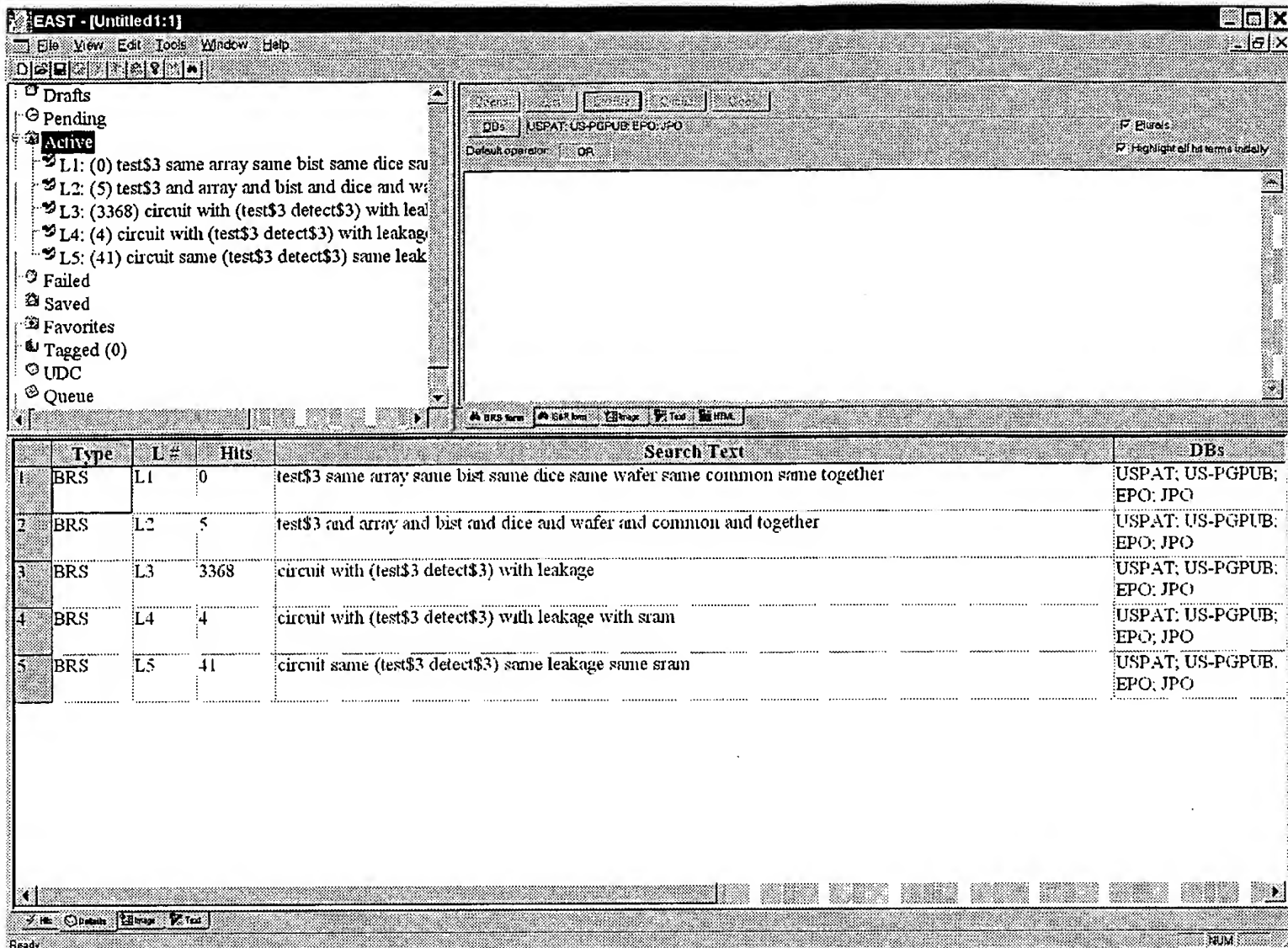
Text

HTML

	Type	L #	Hits	Search Text	DBs
1	BRS	L1	0	memory same (global adj (wordline word-line word)) same (global adj (bitline bit-line bit)) same test\$3 same (conductive conductor conducting)	USPAT; US-PGPUB; EPO; JPO
2	BRS	L2	2	memory and (global adj (wordline word-line word)) and (global adj (bitline bit-line bit)) and test\$3 and (conductive conductor conducting)	USPAT; US-PGPUB; EPO; JPO

Ready

NUM



EAST - [Untitled1:1]

File View Edit Tools Window Help

DB: USPAT:US-PGPUB:EPO:JPO

Default operator: OR

Highlight all hit items initially

L6: (6568) test\$3 and structure and leakage and
L7: (1427) 6 and complement
L8: (325) 7 and (single adj cell)
L9: (220) 8 and pad
L10: (214) 9 and measur\$3
L11: (214) 10 and element
L12: (203) 11 and average
L14: (201) 12 and substrate
L16: (1) 14 and join

Failed
Saved

	Type	L #	Hits	Search Text	DBs
1	BRS	L1	51	ram and test\$3 and measur\$3 and (current adj leakage) and common and conduct\$3 and line	USPAT: US-PGPUB; EPO: JPO
2	BRS	L2	0	(array with cell) same (connect\$3 with together with comunon) same conduct\$3 same (single adj cell)	USPAT: US-PGPUB; EPO: JPO
3	BRS	L3	83	(array with cell) and (connect\$3 with together with comunon) and conduct\$3 and (single adj cell)	USPAT: US-PGPUB; EPO: JPO
4	BRS	L4	32	3 and leakage	USPAT: US-PGPUB; EPO: JPO
5	BRS	L5	12	4 and test\$3	USPAT: US-PGPUB; EPO: JPO
6	BRS	L6	6568	test\$3 and structure and leakage and current and common and connect\$3 and together and conduct\$3	USPAT: US-PGPUB; EPO: JPO
7	BRS	L7	1427	6 and complement	USPAT: US-PGPUB; EPO: JPO
8	BRS	L8	325	7 and (single adj cell)	USPAT: US-PGPUB; EPO: JPO
9	BRS	L9	220	8 and pad	USPAT: US-PGPUB; EPO: JPO
10	BRS	L10	214	9 and measur\$3	USPAT: US-PGPUB; EPO: JPO
11	BRS	L11	214	10 and element	USPAT: US-PGPUB; EPO: JPO
12	BRS	L12	203	11 and average	USPAT: US-PGPUB; EPO: JPO
13	BRS	L14	201	12 and substrate	USPAT: US-PGPUB; EPO: JPO
14	BRS	L16	1	14 and join	USPAT: US-PGPUB; EPO: JPO

Ready

EAST - [Untitled1:1]

File View Edit Tools Window Help

Drafts
Pending
Active
L2: (0) (test\$3 adj structure) same array same cell s
L3: (23) (test\$3 adj structure) and array and cell an
Failed
Saved
Favorites
Tagged (0)
UDC
Queue
Trash

USPAT; US-PGPUB; EPO; JPO

Default operator: OR

Highlight all hits in body

	Type	L #	Hits	Search Text	DBs
1	BRS	L2	0	(test\$3 adj structure) same array same cell same (conduct\$3 adj line) same together same common	USPAT; US-PGPUB; EPO; JPO
2	BRS	L3	23	(test\$3 adj structure) and array and cell and (conduct\$3 adj line) and together and common	USPAT; US-PGPUB; EPO; JPO

Ready

NUM

EAST - [default1.wsp:1]

File View Edit Tools Window Help

Drafts
Pending
Active
L1: (1022) sram and current
L2: (106) sram and (current
L3: (42) 2 and test\$3 and
L4: (7) 3 and common and 1
L5: (1) "5636163". PN.
L6: (1) "4710897". PN.
Failed
Saved
Favorites

Search [Hit] [Browse] [Queue] [Clear]
DBs: USPAT;US-PGPUB;EPO;JPO ☒ Plurals
Default operator: OR ☒ Highlight all hit terms initial

BRS 1... IS&R... Image Text HTML

	Type	L #	Hits	Search Text	DBs	Time S
1	BRS	L1	1022	sram and current and leakage and measur\$3	USPAT ; US-PG	2003/04/19
2	BRS	L2	106	sram and (current adj leakage) and measur\$3	USPAT ; US-PG	2003/04/19
3	BRS	L3	42	2 and test\$3 and structure	USPAT ; US-PG	2003/04/19
4	BRS	L4	7	3 and common and line and pad	USPAT ; US-PG	2003/04/19
5	BRS	L5	1	"5636163". PN.	USPAT	2003/04/19
6	BRS	L6	1	"4710897". PN.	USPAT	2003/04/19

Start [Icons] 1:12 PM

EAST - (default).wsp:1

File View Edit Tools Window Help

Search Edit Browse Queue Clear

DBs: USPAT, US-PGPUB, EPO, JPO ☒ Plurals ☒ Highlight all hit terms initial

Default operator: OR

BRS f... I&R... Image Text HTML

Drafts
Pending
Active
L1: (1022) sram and current
L2: (106) sram and (current
L3: (42) 2 and test\$3 and
L4: (7) 3 and common and 1
Failed
Saved
Favorites
Tagged (1)
UDC

	Type	L #	Hits	Search Text	DBs	Time S
1	BRS	L1	1022	sram and current and leakage and measur\$3	USPAT	2003/04/19
2	BRS	L2	106	sram and (current adj leakage) and measur\$3	US-PG USPAT	2003/04/19
3	BRS	L3	42	2 and test\$3 and structure	US-PG USPAT	2003/04/19
4	BRS	L4	7	3 and common and line and pad	US-PG USPAT	2003/04/19

Start [Icons] 11:14 AM

EAST - [default1.wsp:1]

File View Edit Tools Window Help

☐ Drafts
☐ Pending
☒ Active
 L1: (2) sram and test\$3 and
☐ Failed
☐ Saved
☐ Favorites
☐ Tagged (0)
☐ UDC
☐ Queue
☐ Trash

Search List Browse Queue Clear

DBs: USPAT:US-PGPUB:EPO:JPO ☒ Plurals

Default operator: OR ☒ Highlight all hit terms initial

sram and test\$3 and measur\$3 and (current adj leakage) and
common and conductive and line and pad

BRS f... IS&R... Image Text HTML

	U	1	Document ID	Issue Date	Pages	Title	Current OR	Current XRef
1	<input type="checkbox"/>	<input type="checkbox"/>	US 20030032292 A1	20030213	62	Fabrication method of semiconductor integrated	438/692	438/690
2	<input type="checkbox"/>	<input type="checkbox"/>	US 5255230 A	19931019	10	Method and apparatus for testing the continuity of	365/201	365/190; 365/203;

Start [Icons] 1:40 PM

EAST - [default1.wsp:1]

File View Edit Tools Window Help

☒ L1: (1022) sram and current
☒ L2: (106) sram and (current
☒ L3: (42) 2 and test\$3 and
☒ L4: (7) 3 and common and 1
☒ L5: (1) "5636163". PN.
☒ L6: (1) "4710897". PN.

Search List Browse Queue Clear

DB: USPAT:US-PGPUB:EPO:JPO ☒ Plurals

Default operator: OR ☒ Highlight all hit terms initial

2 and test\$3 and structure

BRS 1... IS&R... Image Text HTML

	U	Document ID	Issue Date	Pages	Title	Current OR	Current XRef
1	<input type="checkbox"/>	<input checked="" type="checkbox"/> US 20020167849 A1	20021114	72	Semiconductor memory device and testing method therefor	365/189.09	
2	<input type="checkbox"/>	<input checked="" type="checkbox"/> US 6534785 B1	20030318	22	Reduced terminal testing system	257/48	257/203; 257/207;
3	<input type="checkbox"/>	<input checked="" type="checkbox"/> US 6424168 B1	20020723	22	Reduced terminal testing system	324/765 -	324/763
4	<input type="checkbox"/>	<input checked="" type="checkbox"/> US 6380798 B1	20020430	29	Semiconductor integrated circuit apparatus	327/534	327/391
5	<input type="checkbox"/>	<input checked="" type="checkbox"/> US 6292009 B1	20010918	23	Reduced terminal testing system	324/765 -	324/763
6	<input type="checkbox"/>	<input checked="" type="checkbox"/> US 6119250 A	20000912	32	Semiconductor integrated circuit	714/718	365/201
7	<input type="checkbox"/>	<input checked="" type="checkbox"/> US 6118138 A	20000912	22	Reduced terminal testing system	257/48	257/203; 257/207;
8	<input type="checkbox"/>	<input checked="" type="checkbox"/> US 5994915 A	19991130	25	Reduced terminal testing system	324/765	324/763
9	<input type="checkbox"/>	<input checked="" type="checkbox"/> US 5976899 A	19991102	23	Reduced terminal testing system	438/14	438/17
10	<input type="checkbox"/>	<input checked="" type="checkbox"/> US 5898186 A	19990427	23	Reduced terminal testing system	257/48	257/203; 257/207;
11	<input type="checkbox"/>	<input checked="" type="checkbox"/> US 4835458 A	19890530	12	Signature analysis technique for defect characterization	324/73.1	324/754; 365/201;
12	<input type="checkbox"/>	<input type="checkbox"/> US 20030052371 A1	20030320	66	Semiconductor integrated circuit device	257/371	257/288; 257/368;

Start [Icons] 1:13 PM

EAST - [default1.wsp.1]

File View Edit Tools Window Help

☐ Drafts
☐ Pending
☒ Active
 L1: (1022) sram and curren
 L2: (106) sram and (curren
 L3: (42) 2 and test\$3 and
 L4: (7) 3 and common and 1
☐ Failed
☐ Saved
☐ Favorites
☐ Tagged (1)
☐ UDC

Search List Browse Queue Clear

DB: USPAT:US-PGPUB:EPO:JPO ☒ Plurals
Default operator: OR ☒ Highlight all hit terms initial

3 and common and line and pad

BRS I... IS&R... Image Text HTML

	U	1	Document ID	Issue Date	Pages	Title	Current OR	Current XRef
1	<input type="checkbox"/>	<input type="checkbox"/>	US 20030052371 A1	20030320	66	Semiconductor integrated circuit device	257/371	257/288; 257/368;
2	<input type="checkbox"/>	<input type="checkbox"/>	US 20030032292 A1	20030213	62	Fabrication method of semiconductor integrated	438/692	438/690
3	<input type="checkbox"/>	<input type="checkbox"/>	US 20010034093 A1	20011025	66	Semiconductor integrated circuit device	438/199	257/E27.06; 257/E27.061;
4	<input type="checkbox"/>	<input type="checkbox"/>	US 6500715 B2	20021231	62	Method of forming a CMOS structure having gate	438/275	257/E21.623; 257/E21.626;
5	<input type="checkbox"/>	<input type="checkbox"/>	US 6307236 B1	20011023	63	Semiconductor integrated circuit device	257/392	257/402; 257/406;
6	<input type="checkbox"/>	<input checked="" type="checkbox"/>	US 6119250 A	20000912	32	Semiconductor integrated circuit	714/718	365/201
7	<input type="checkbox"/>	<input type="checkbox"/>	US 5844416 A	19981201	12	Ion-beam apparatus and method for analyzing and	324/750	

Start [Icons] 11:13 AM